IN THE UNITED STATES PATENT AND TRADEMARK OFFICE ATTORNEY DOCKET NO. 047071-0109

Applicant:

Harry A. ATWATER et al.

Title:

WAFER BONDED EPITAXIAL TEMPLATES FOR SILICON

HETEROSTRUCTURES

Appl. No.:

10/784,586

Filing Date:

02/23/2004

Examiner:

Unassigned

Art Unit:

1764

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR §1.56

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Submitted herewith on Form PTO/SB/08 a listing of the documents cited by or submitted to the U.S. PTO in parent application Serial No. 10/125,133, filed April 17, 2002. As provided in 37 CFR §1.98(d), copies of the documents are not being provided since they were previously submitted to the United States Patent & Trademark Office in the above-identified parent application.

The submission of any document herewith, which is not a statutory bar, is not intended as an admission that such document constitutes prior art against the claims of the present application or that such document is considered material to patentability as defined in 37 CFR §1.56(b). Applicants do not waive any rights to take any action which would be appropriate to antedate or otherwise remove as a competent reference any document which is determined to be a *prima facie* art reference against the claims of the present application.

TIMING OF THE DISCLOSURE

The listed documents are being submitted in compliance with 37 CFR §1.97(b), before the mailing date of the first Office Action on the merits.

RELEVANCE OF EACH DOCUMENT

The relevance of the documents is explained in the parent application.

Applicants respectfully request that any listed document be considered by the Examiner and be made of record in the present application and that an initialed copy of Form PTO/SB/08 be returned in accordance with MPEP §609.

The Commissioner is hereby authorized to charge any additional fees which may be required regarding this application under 37 CFR §§ 1.16-1.17, or credit any overpayment, to Deposit Account No. 19-0741. Should no proper payment be enclosed herewith, as by a check being in the wrong amount, unsigned, post-dated, otherwise improper or informal or even entirely missing, the Commissioner is authorized to charge the unpaid amount to Deposit Account No. 19-0741.

Respectfully submitted,

Attorney for Applicant Registration No. 43,445

Leon Radomsky

Date January 7, 2005

FOLEY & LARDNER LLP

Customer Number: 22428

Telephone:

(202) 672-5300

Facsimile:

(202) 672-5399

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Substitute for form 1449B/PTOR PRADEMARY INFORMATION DISCLOSURE

> STATEMENT BY APPLICANT Date Submitted: 1/7/05

(use as many sheets as necessary)

Sheet 1 of 7

C	omplete if Known	
Application Number	10/784,586	
Filing Date	02/23/2004	
First Named Inventor	Harry A. ATWATER et al.	
Group Art Unit	1764	
Examiner Name	Unassigned	
Attorney Docket Number	047071-0109	

	•			U.S. PATENT DOCUMENTS	3	
Examiner Initials*	-	U.S. Patent D	ocument	Name of Datastas Assistants	Date of Publication of	Pages, Columns, Lines, Where Relevant
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Signature	Considered	

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⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

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	Substitute for	or form 1449E	B/PTO		Complete if Known			
	INFORMATI	ON DISCLO	SURE	Application Number	10/784,586			
	STATEMEN	T BY APPL	ICANT	Filing Date	02/23/2004			
	Data Su	bmitted: 1/7/	IOE	First Named Inventor	Harry A. ATWATER et al.			
	Date Su	omitted. 1777	703	Group Art Unit	1764			
	(use as many :	sheets as ne	ecessary)	Examiner Name	Unassigned			
Sheet	2	of	7	Attorney Docket Number	047071-0109			

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Examiner Cite No.1	Cita	U.S. Patent (Document	Name of Patentee or Applicant of Cited Document	Date of Publication of	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear			
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Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ⁶
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Substitute for form 1449B/PTO Complete if Known **INFORMATION DISCLOSURE** 10/784,586 **Application Number** STATEMENT BY APPLICANT Filing Date 02/23/2004 Harry A. ATWATER et al. **First Named Inventor** Date Submitted: 1/7/05 **Group Art Unit** 1764 (use as many sheets as necessary) **Examiner Name** Unassigned of Sheet 3 7 047071-0109 **Attorney Docket Number**

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No. ¹	Number	Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Cited Document MM-DD-YYYY	Passages or Relevant Figures Appear				
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Substitute for form 1449B/PTO Complete if Known **INFORMATION DISCLOSURE Application Number** 10/784,586 STATEMENT BY APPLICANT **Filing Date** 02/23/2004 Harry A. ATWATER et al. **First Named Inventor** Date Submitted: 1/7/05 1764 **Group Art Unit** (use as many sheets as necessary) **Examiner Name** Unassigned of 7 Sheet 4 **Attorney Docket Number** 047071-0109

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				U.S. PATENT DOCUMENTS		
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Substitute for form 1449B/PTO Complete if Known **INFORMATION DISCLOSURE Application Number** 10/784,586 STATEMENT BY APPLICANT Filing Date 02/23/2004 First Named Inventor Harry A. ATWATER et al. Date Submitted: 1/7/05 **Group Art Unit** 1764 (use as many sheets as necessary) **Examiner Name** Unassigned of 7 Sheet 6 047071-0109 **Attorney Docket Number**

				U.S. PATENT DOCUMENTS		-
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Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.					
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Examiner	Date
Signature	Considered

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	STATEMENT	BY APPL	ICANT	Filing Date	02/23/2004			
	Date Sub	mitted: 1/7	/OS	First Named Inventor	Harry A. ATWATER et al.			
	Date Subi	initted. 177	103	Group Art Unit	1764			
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Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.			
	A60	ZAHLER et al., Ge/Si Wafer Bonded Epitaxial Templates for GaAs/Si Heterostructures, (Abstract), MRS 2002 Fall Meeting, (11/2002)			
	A61	MORRAL et al., Bonding and Layer Transfer Process of InP on Silicon for the Elaboration of the Botton Double Heterostructure of 4-Junction High Efficiency Solar Cells, (Abstract), MRS 2002 Fall Meeting, (11/2002)			
	A62	MORRAL et al., Assessment of Optical and Structural Properties of III-V Semiconductors Grown on InP/Si and Ge/Si Wafer Bonded Epitaxial Templates with Application to a Four-Junction Solar Cell, (Abstract), MRS 2003 Spring Meeting, (04/2003)			
	A63	MORRAL et al., Electrical and Structural Characterization of the Interface of Wafer Bonded InP/Si, MRS 2003 Spring Meeting, (04/2003)			
	A64	MORRAL et al., The Role of Hydrogen in H-Induced Exfoliation and Layer Transfer on InP, (Abstract), MRS 2004 Spring Meeting, (04/2004)			

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